

Applications of high efficiency FELs for EUV lithography

Patrick Naulleau

Center for X-ray Optics

Lawrence Berkeley National Laboratory



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Outline

- Semiconductor industry trends
- Introduction to EUV Lithography
- Future power needs
- Key FEL source requirements

Semiconductor industry is huge economic driver

\$59 Billion

Semiconductor
R&D (2017)



\$412 Billion

Semiconductor
device market
(2017)



\$2.0 Trillion

Global electronics
market (2017)

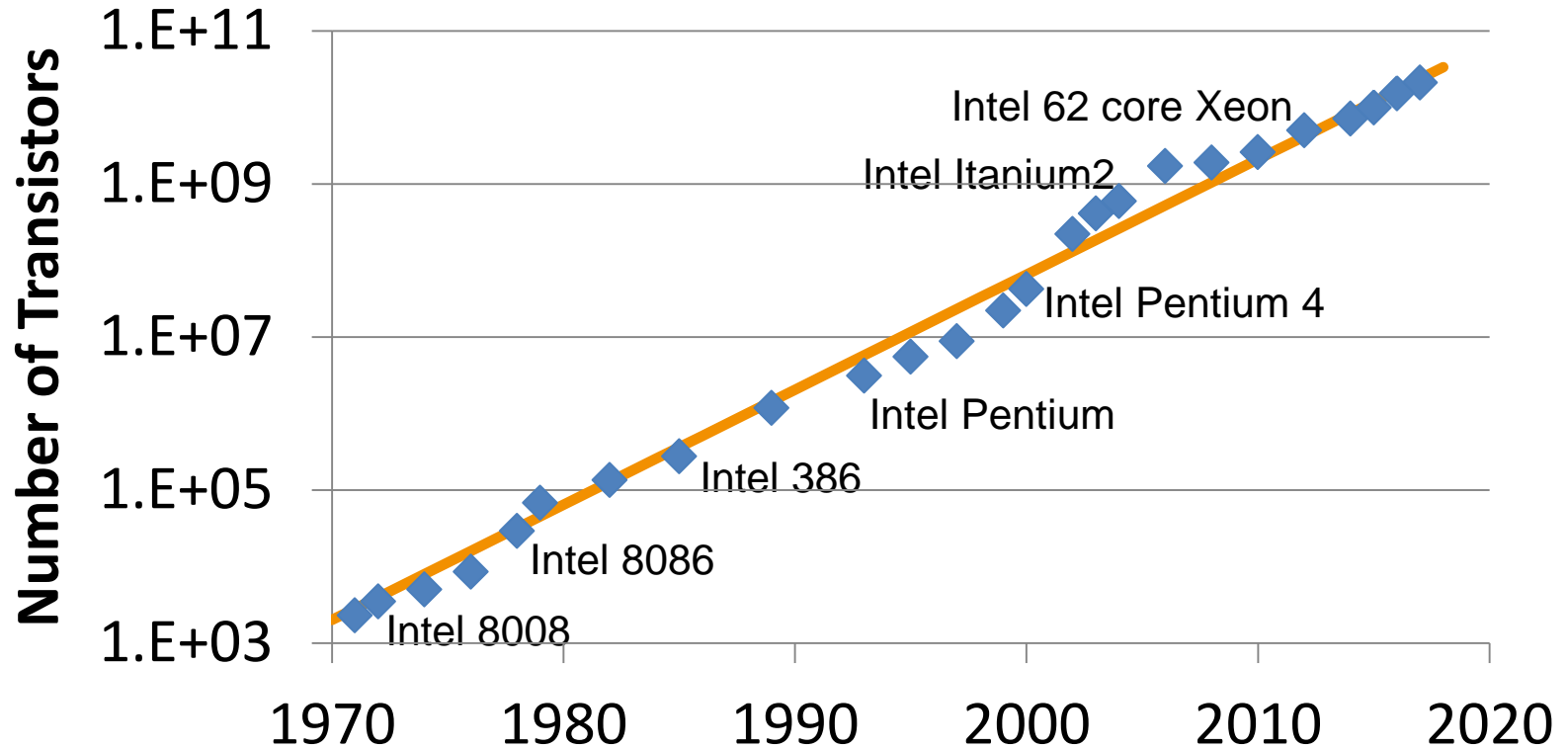
SIA, www.persistencemarketresearch.com

“By 2020, [expected] cost of between \$15 and \$20 billion for a leading-edge fab”

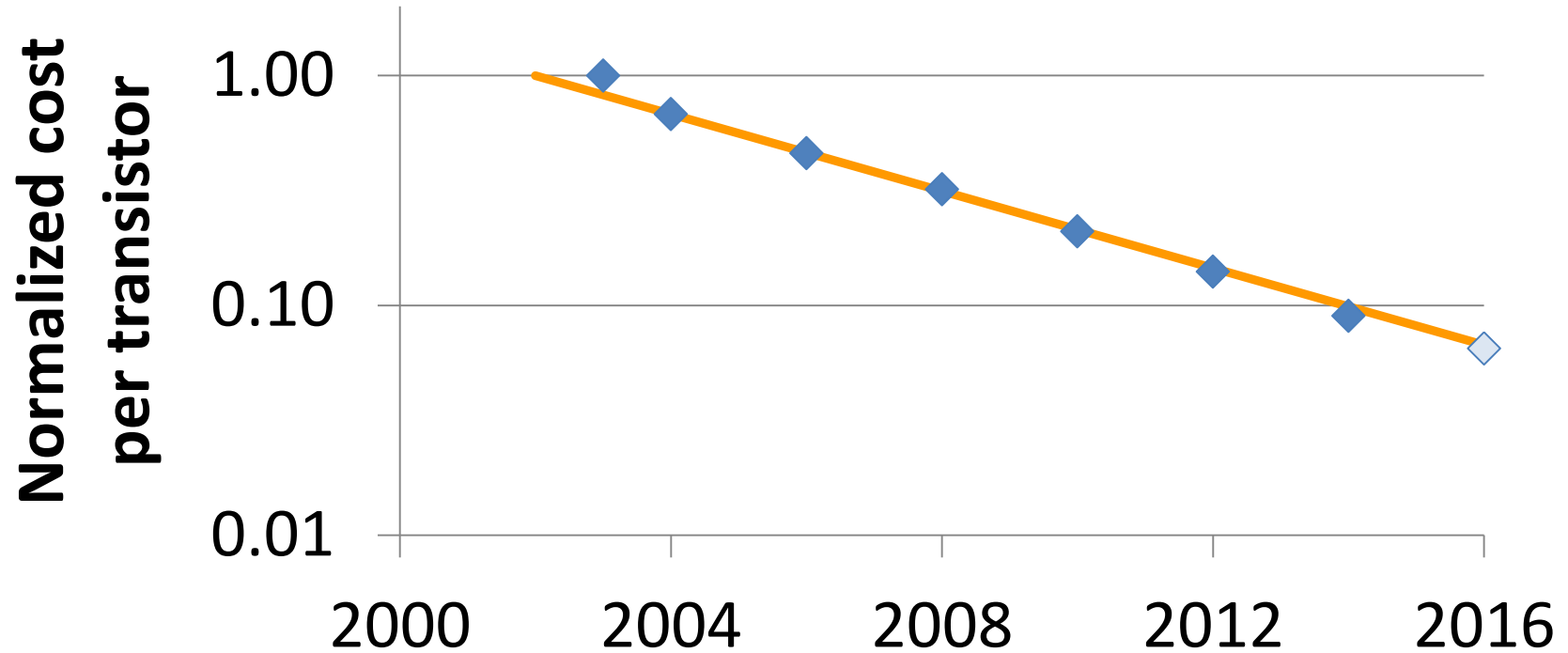
EE Times



Industry growth enabled by Moore's Law: transistors double every two years



The other half of Moore's Law: density increase at shrinking cost



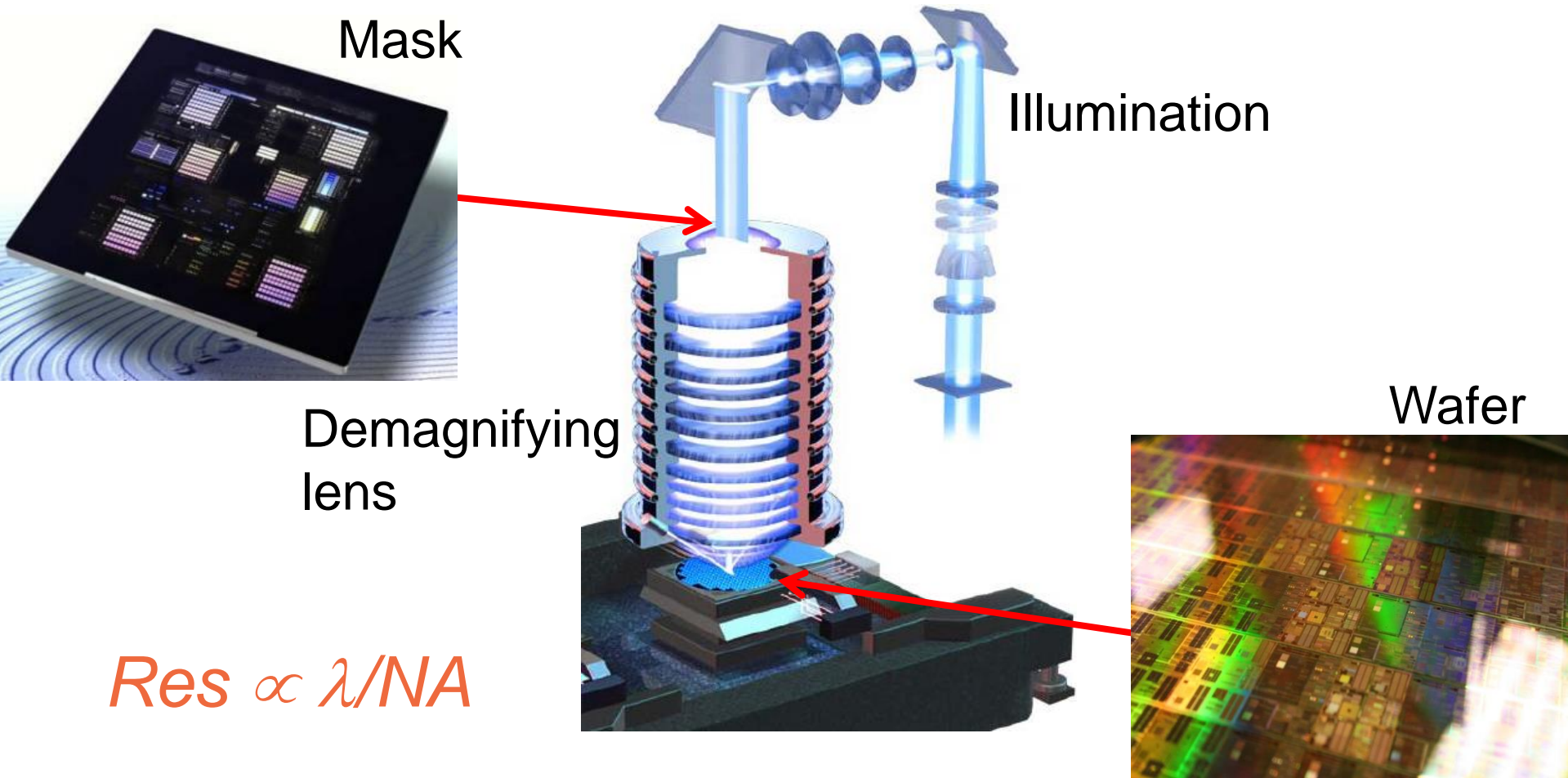
Data from Intel (<http://www.pcworld.com/article/2887275/intel-moores-law-will-continue-through-7nm-chips.html>)

128 GB microSD
\$59.99



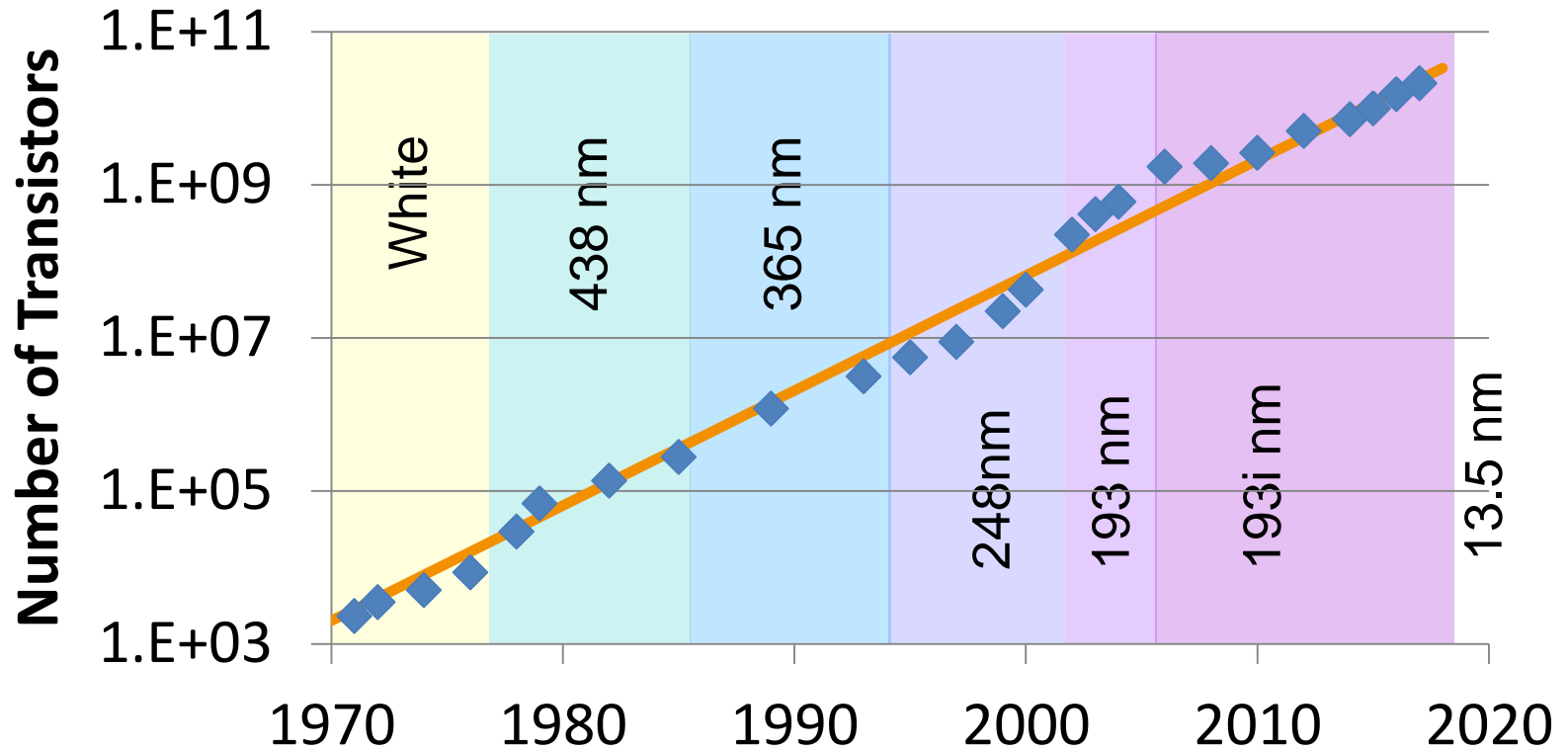
Would have cost
\$256 billion in 1970

Lithography drives shrink

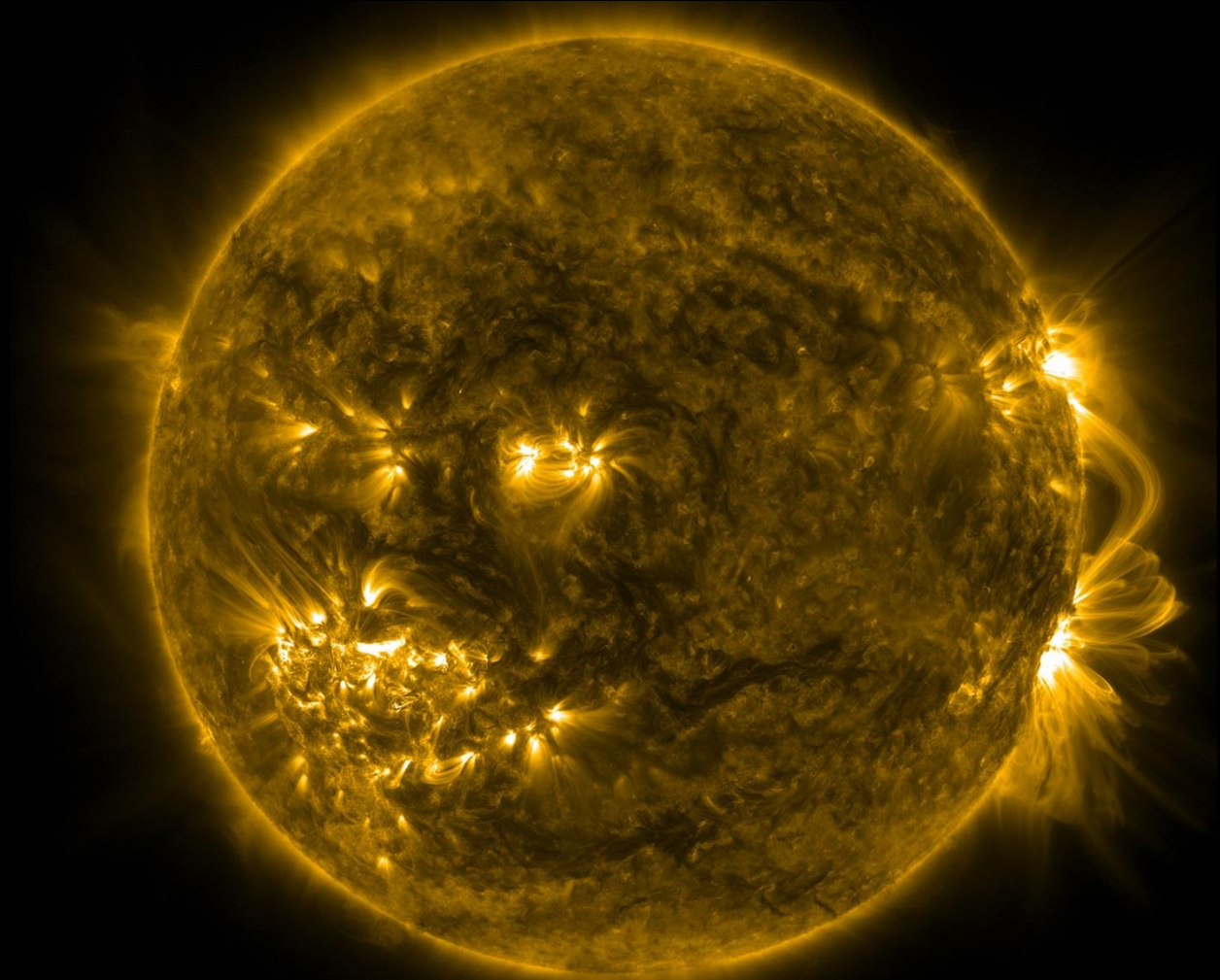


$$Res \propto \lambda/NA$$

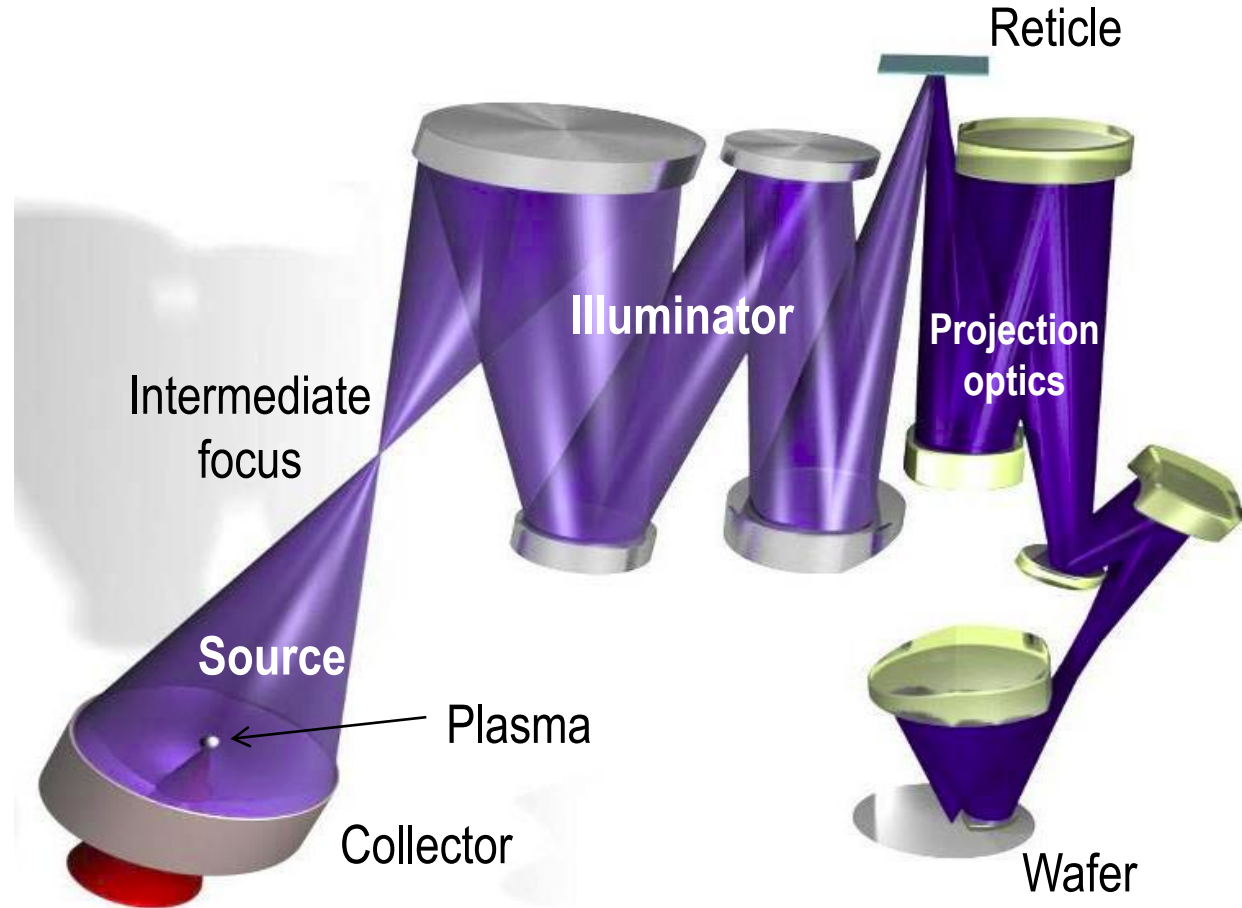
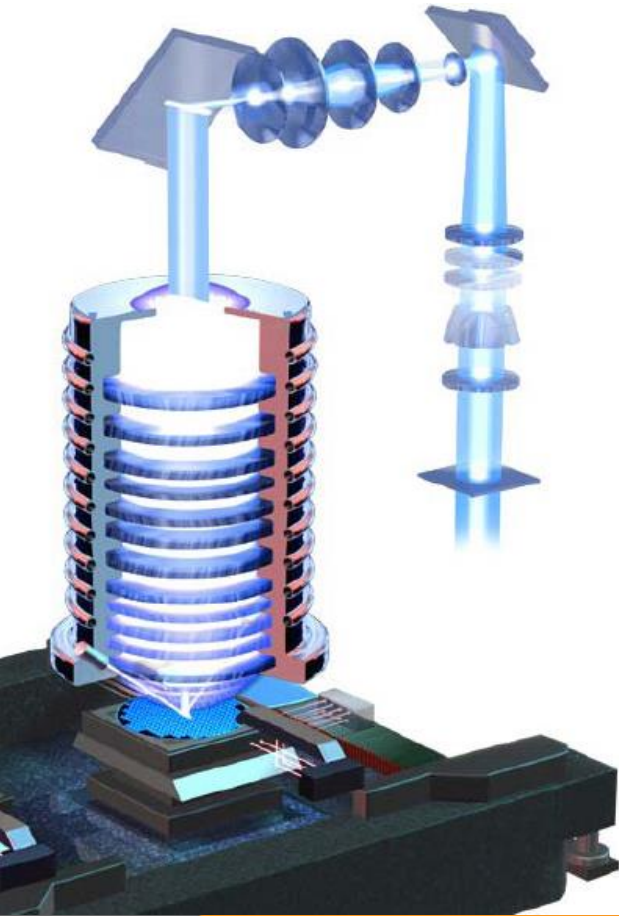
Moore's Law driven by wavelength shrink



How does EUV lithography work?



EUVL: optical lithography at $\lambda = 13.5$ nm

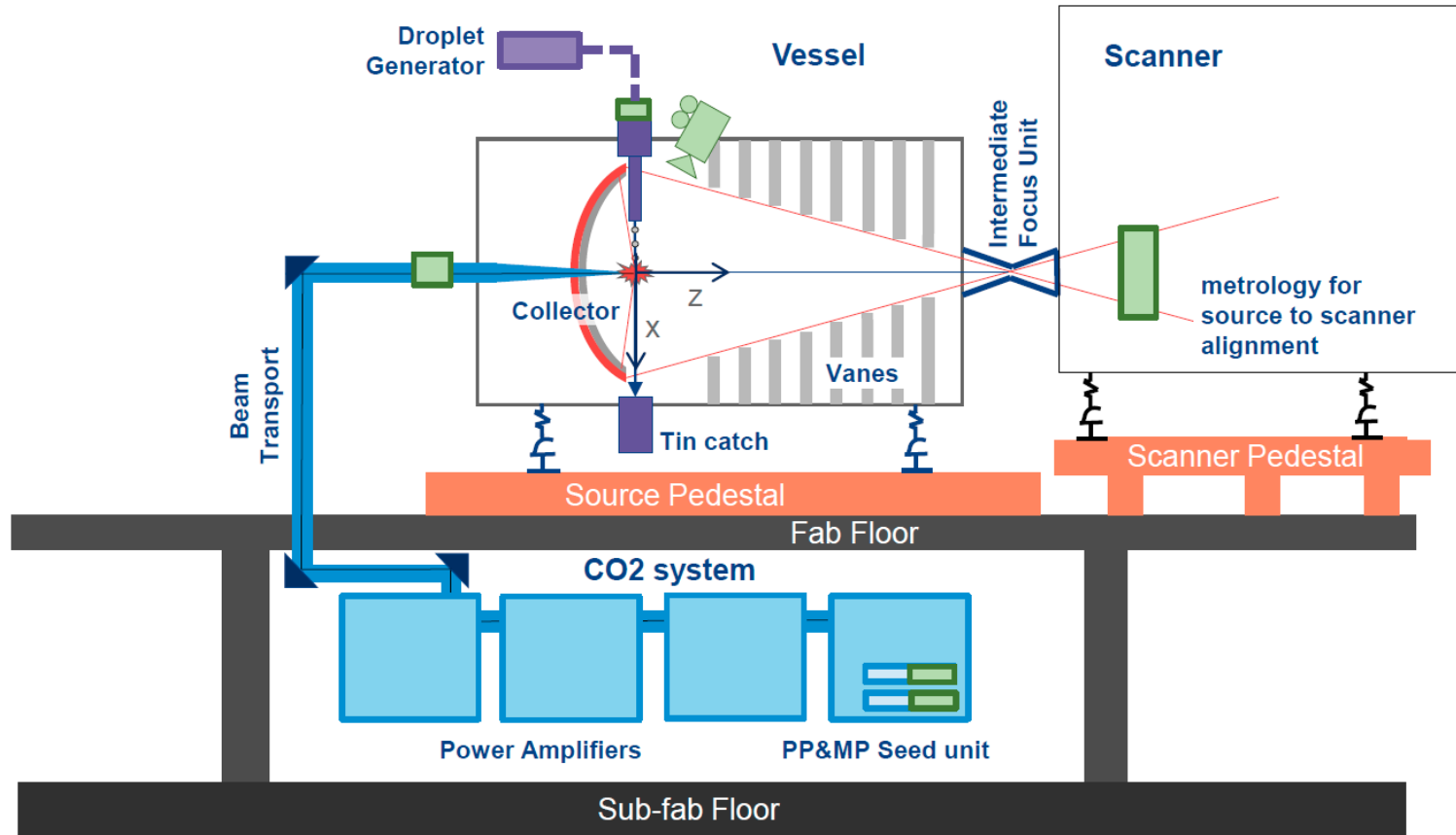


Near term source power requirements

| | | |
|---|--------------------|--------|
| Wafer Throughput | wafer/h | 145 |
| Total wafer time | sec | 24.8 |
| Stage motion overhead | sec | 18 |
| Wafer exposure time | sec | 6.8 |
| Wafer diameter | mm | 300 |
| Wafer fill factor | % | 89% |
| Resist Sensitivity | mJ/cm ² | 15 |
| Required Power at Wafer | W | 1.38 |
| | | |
| POB reflectivity (0.66 ⁶) | % | 8.27% |
| Mask reflectivity | % | 62% |
| Illuminator reflectivity (0.66 ⁴) | % | 18.97% |
| Overfill efficiency | % | 75% |
| Pellicle efficiency | % | 76% |
| Total Optical Efficiency | % | 0.55% |
| | | |
| Required collected source power | W | 250 |

**Required
source power
= 250W**

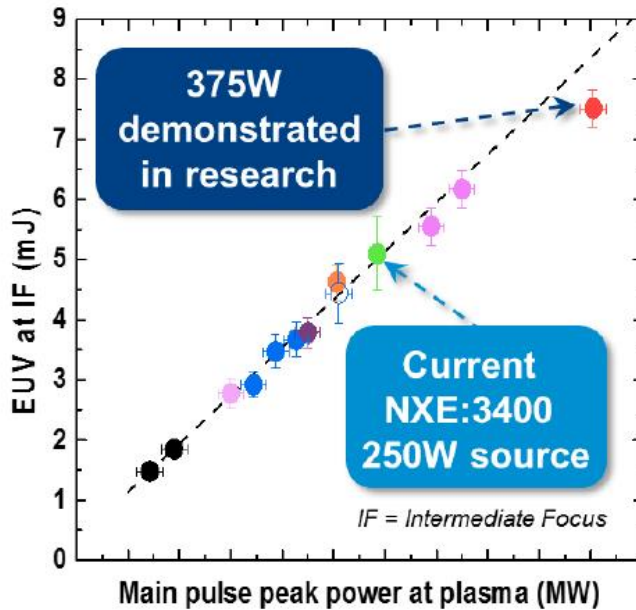
EUV Source - Principle of operation



LPP source status

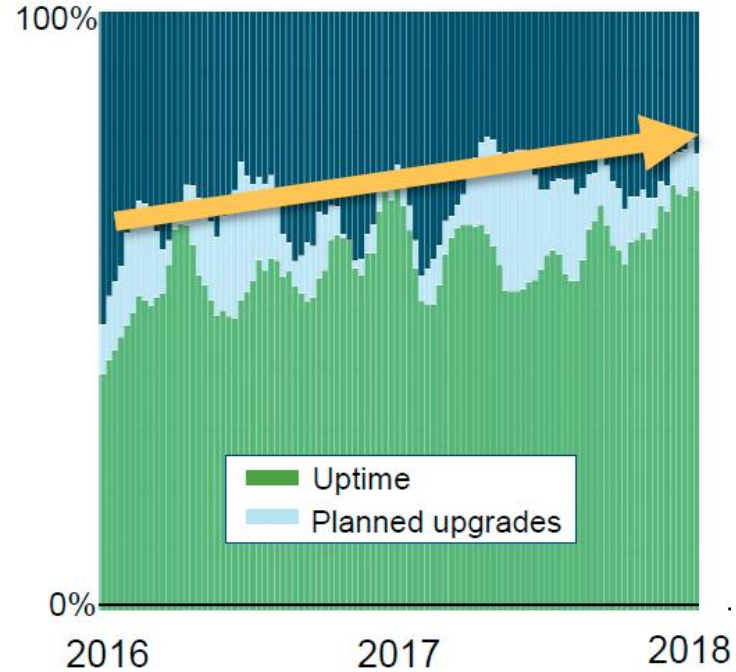
EUV Source & Throughput

Proven Power¹ & Wafers/Hour²



EUV Availability

Uptime %



ASML, SPIE Advanced Lithography Conference 2018

Future source power needs?



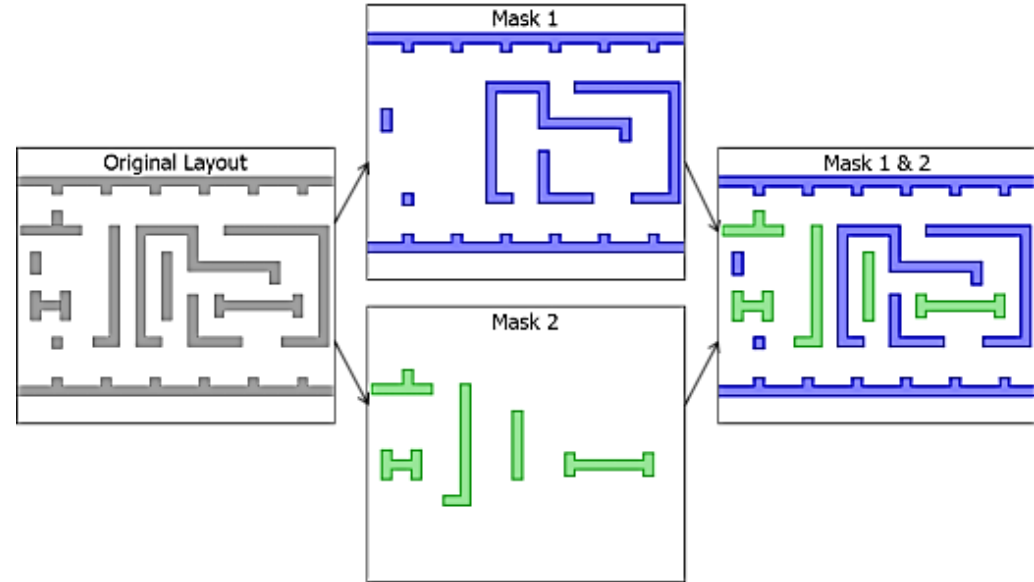
Key variable assumptions in 250W number

- Throughput = 145 Wafers/hr
- Wafer size = 300 mm
- Dose = 15 mJ/cm²

Source power requirements expected to grow significantly in the future

Double patterning

- Throughput = 220 wafers/hr
- Stage overhead = 12 seconds

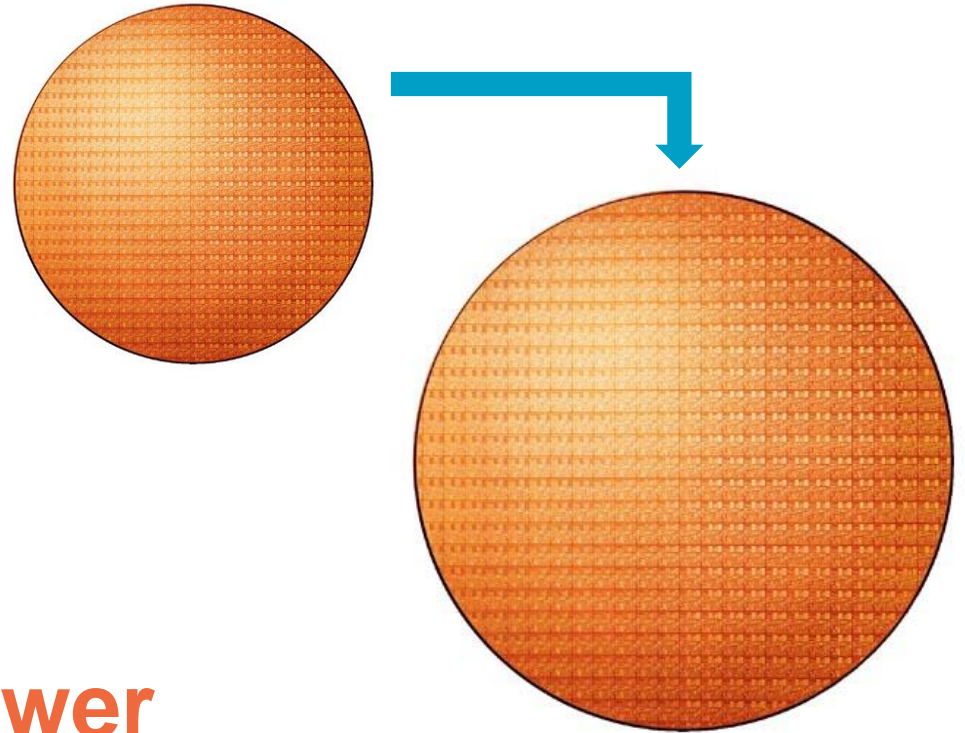


1.6x more power

Source power requirements expected to grow significantly in the future

450-mm wafers

- Throughput
= 105 wafers/hr
- Stage overhead*
= 12 seconds



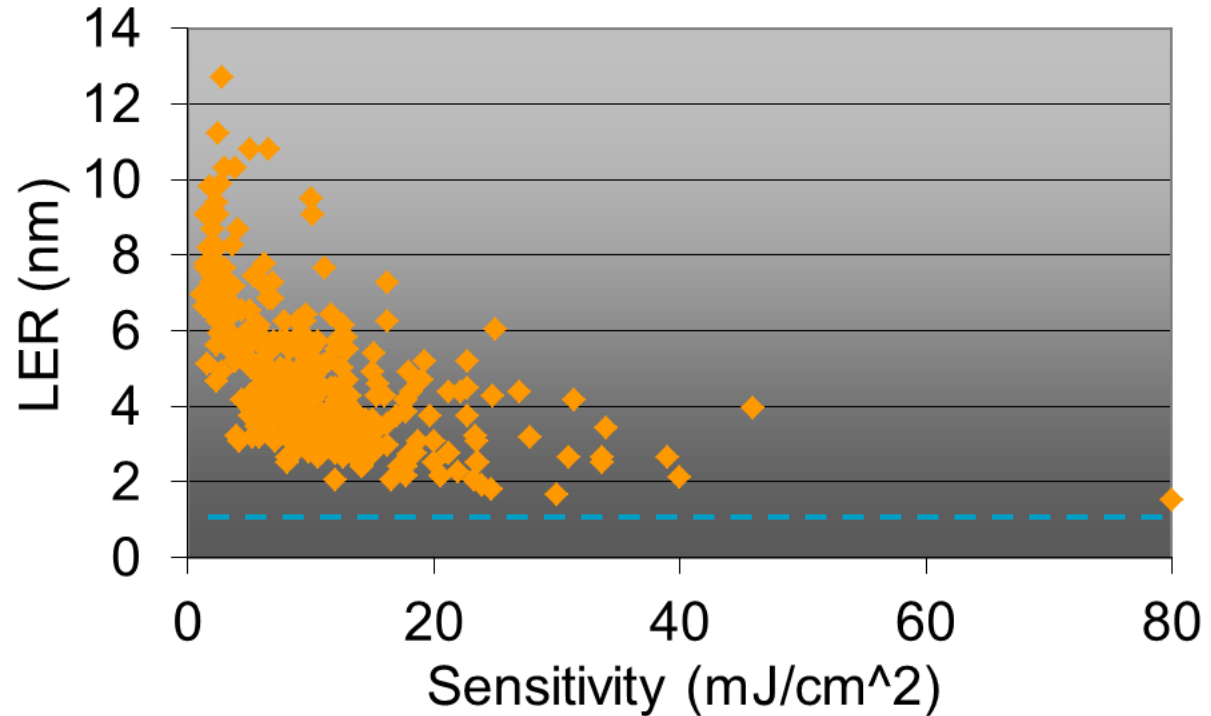
1.5x more power

* Normalized to 300-mm wafer

Source power requirements expected to grow significantly in the future

Dose

- 15 mJ/cm² likely not enough in the future



Source power requirements expected to grow significantly in the future

Dose

- 15 mJ/cm² likely not enough in the future

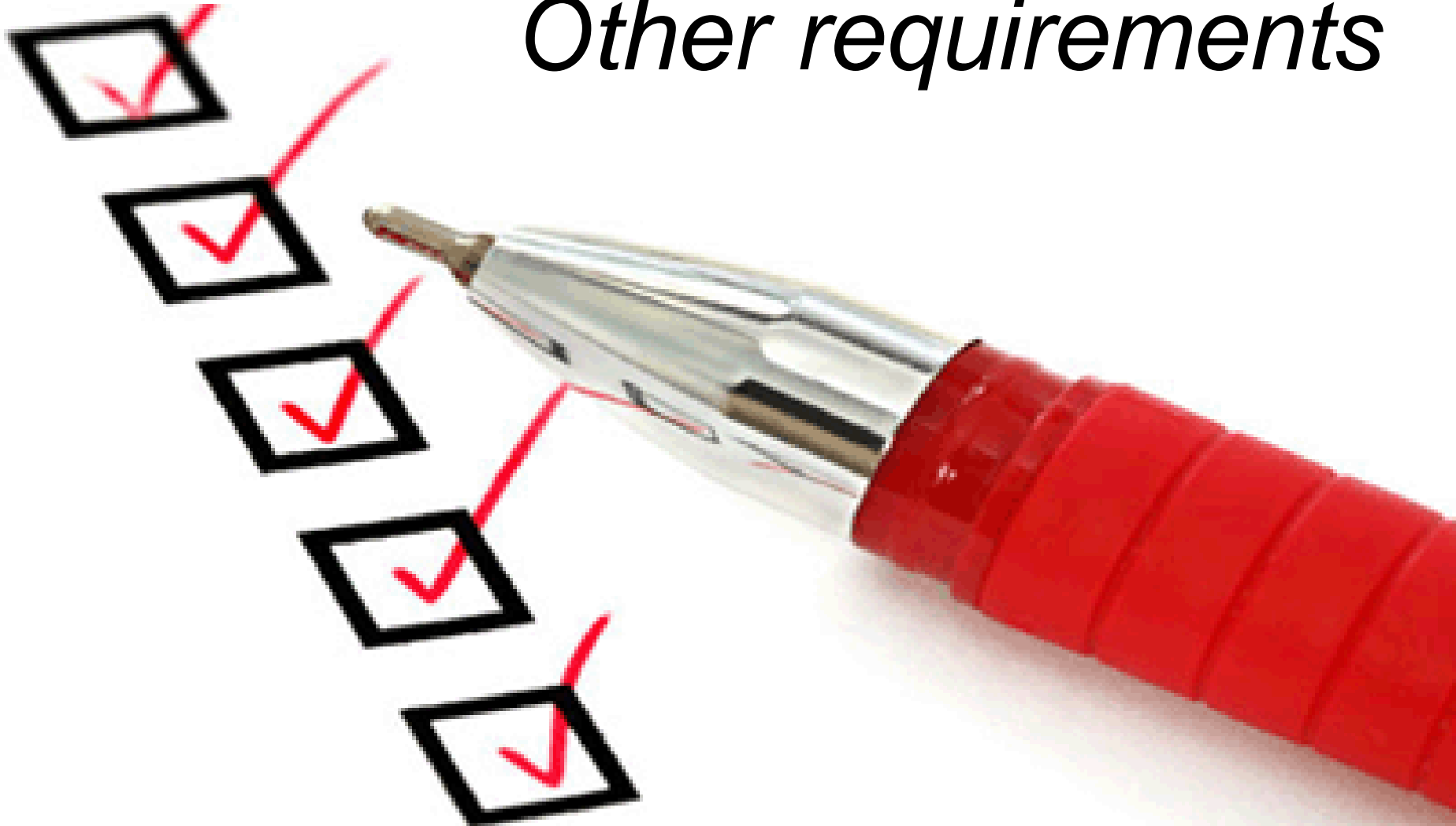
| | Resist CA-C | Resist CA-A | Resist NCA-A |
|--|-------------|-------------|--------------|
| Resolution (nm) | 15 | 16 | 15 |
| LWR (nm) | 3.8 | 3.1 | 1.5 |
| Dose (mJ/cm ²) | 22 | 30 | 80 |
| Shot noise scaled dose (mJ/cm ²) | 162 | 147 | 92 |

2-4x more power

$$LWR \propto 1/\sqrt{dose}$$

**Depending on resist performance,
future power needs could range
from 500W to 2000W**

Other requirements



Size: about the size of a shipping container

- Allowable source footprint:
~ 10m x 3m



Reliability: Require > 95% uptime



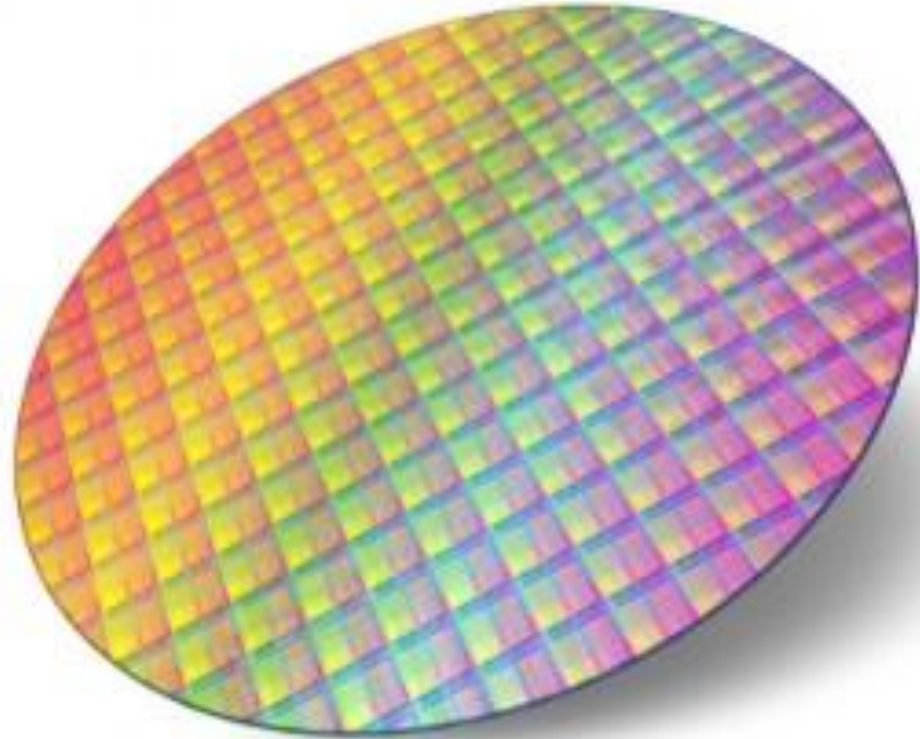
Even better uptime required
if driving multiple tools

Source power stability

Need $<1\%$ with 1 ms integration window

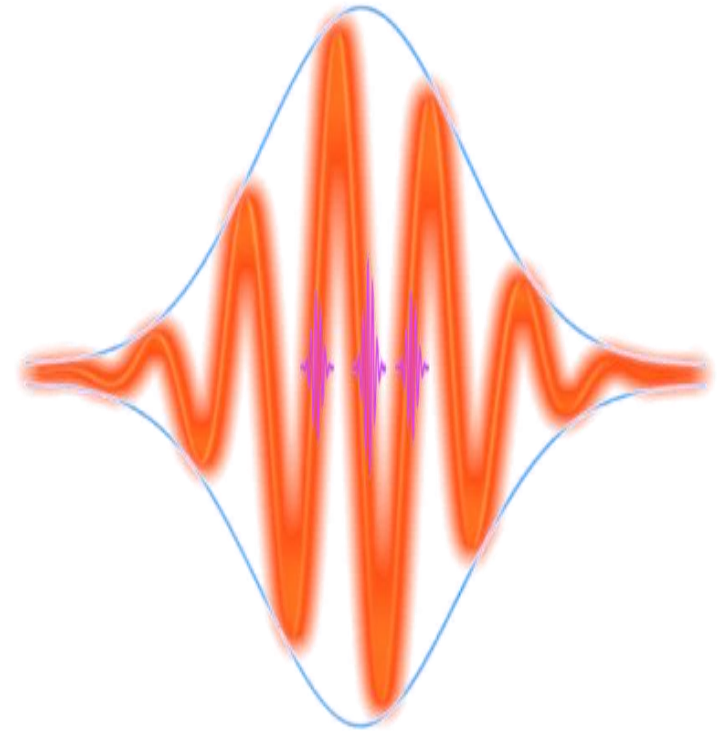
- Implies rep rate $>1\text{kHz} \times \text{FPN}^2$
- 30% pulse noise \Rightarrow rep rate $> 900\text{kHz}$

FPN = fractional pulse noise



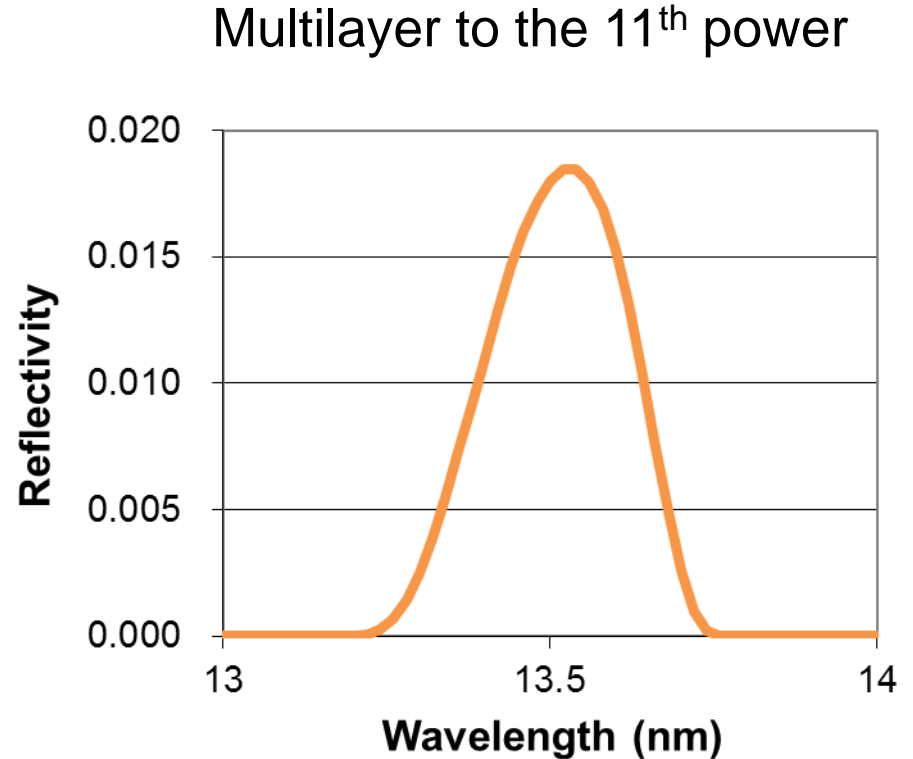
Pulse length

- Multilayer BW limits require pulse > 2.5 fs
- Longer is better to avoid optics damage issues



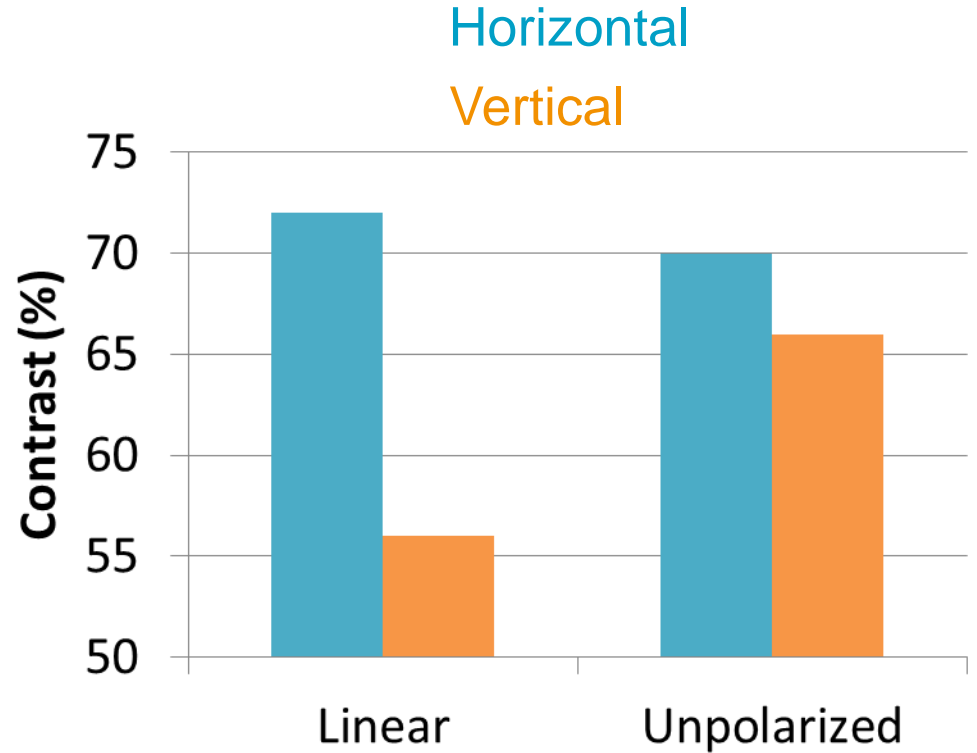
Bandwidth

- Multilayer mirrors require bandwidth $< \pm 0.14\text{nm}$ (1%)
- Narrower bandwidth = greater effective optical throughput
 - $\pm 0.02\text{nm}$ BW would provide 28% effective power boost



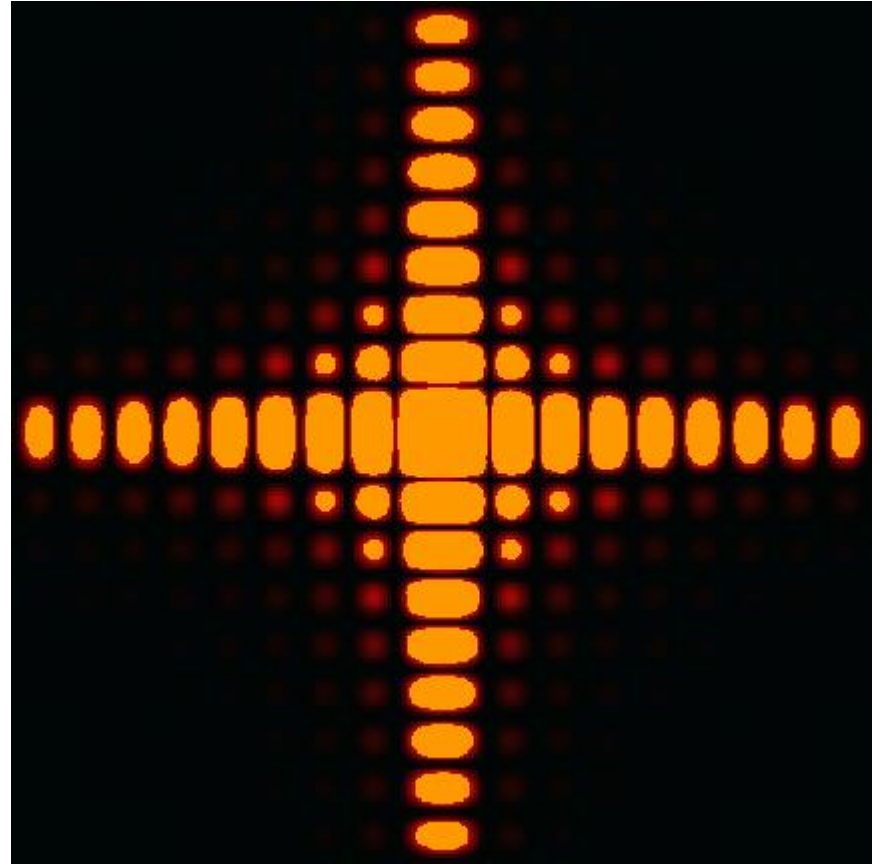
Polarization

- Linear polarized light causes significant imaging anisotropy
- If it can be manipulated, polarization can be viewed as asset



Coherence

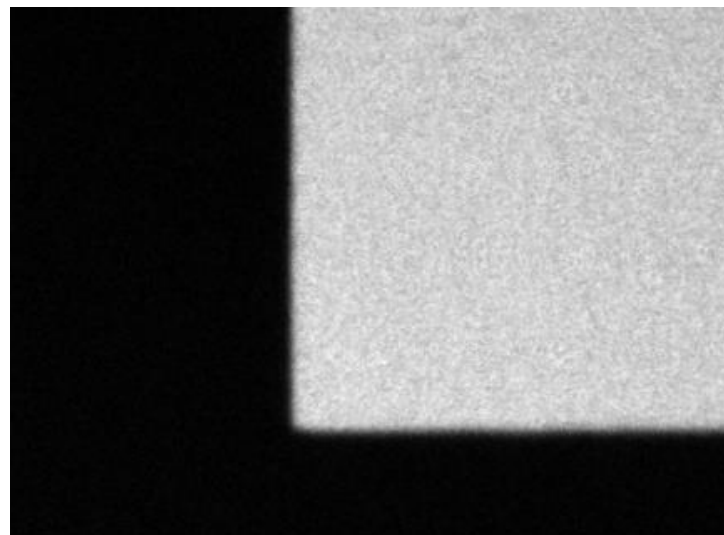
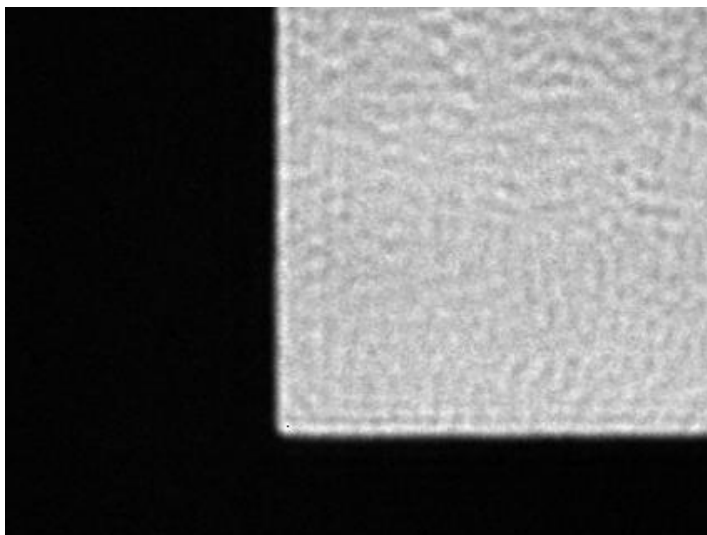
- No longitudinal coherence needed
- No lateral coherence needed (coherence must be destroyed)



Coherent

Partial coherence

Defocus



Summary

- EUV is on its way
- We need creative solutions to carry the technology well into the future

CXRO

